**Top View** 



## IRFH5207TR2PBF-VB Datasheet N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
	0.0048 at V <sub>GS</sub> = 10 V	60				
80	0.0050 at V <sub>GS</sub> = 7.5 V	60	25 nC			
	0.0064 at V <sub>GS</sub> = 4.5 V	60				

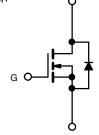
#### **FEATURES**

- Trench power MOSFET
- 100 % Rq and UIS tested

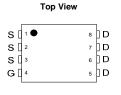


#### **APPLICATIONS**

- · Primary side switching
- Synchronous rectification
- DC/AC inverters







N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	80			
Gate-Source Voltage	V <sub>GS</sub>	± 20			
	T <sub>C</sub> = 25 °C		60 <sup>a</sup>		
Continuous Dunis Comment /T 150 °C)	T <sub>C</sub> = 70 °C		60 a		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	23.8 b, c		
	T <sub>A</sub> = 70 °C		19 <sup>b, c</sup>	_	
Pulsed Drain Current (t = 300 μs)		I <sub>DM</sub>	100	A	
Continuous Courses Dunis Dinds Coursest	T <sub>C</sub> = 25 °C		60 <sup>a</sup>		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	5.6 b, c		
ngle Pulse Avalanche Current		I <sub>AS</sub>	35		
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	61	mJ	
	T <sub>C</sub> = 25 °C		104		
Manipular Davier Dispiration	T <sub>C</sub> = 70 °C	D	66.6	W	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	6.25 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		4 b, c		
Operating Junction and Storage Temperature R	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150			
Soldering Recommendations (Peak Temperature	-	260	— °C		

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient b, f	t ≤ 10 s	R <sub>thJA</sub>	15	20	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	0.9	1.2	C/VV		

#### **Notes**

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
  d. The DFN 5Xx6 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 54 °C/W.



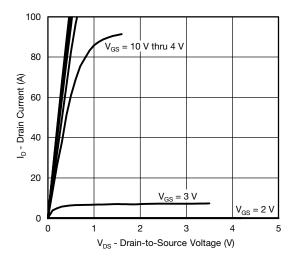
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			47	-	1400	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	In = 250 UA		-5.7	-	mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.2	-	2.8	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
7 0 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	I <sub>DSS</sub>	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C	-	-	10		
On-State Drain Current a	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30	-	-	Α	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A	-	0.0048	-		
Drain-Source On-State Resistance a	R <sub>DS(on)</sub>	$V_{GS} = 7.5 \text{ V}, I_D = 20 \text{ A}$	-	0.0050	-	Ω	
	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	$V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$	-	0.0064	-	1	
prward Transconductance <sup>a</sup> $g_{fs}$ $V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		-	68	-	S		
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>		-	2800	-		
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	1100	-	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	93	-		
Total Gate Charge	Q <sub>g</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$	-	57	86		
		$V_{DS} = 40 \text{ V}, V_{GS} = 7.5 \text{ V}, I_D = 20 \text{ A}$	-	42	63		
			-	25	38	nC	
Gate-Source Charge		$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$	-	8.5	-		
Gate-Drain Charge	$Q_{gd}$		-	10	-		
Output Charge	Q <sub>oss</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V	-	70	105	1	
Gate Resistance	$R_{g}$	f = 1 MHz	0.3	0.95	1.9	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>		-	9	18	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 2 \Omega$	-	12	24		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20$ Å, $V_{GEN} = 10$ V, $R_g = 1$ $\Omega$	-	34	68		
Fall Time	t <sub>f</sub>		-	7	14		
Turn-On Delay Time	t <sub>d(on)</sub>		-	16	32		
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 2 \Omega$	-	15	30		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{GEN} = 7.5 \text{ V}, R_g = 1 \Omega$	-	32	64		
Fall Time	t <sub>f</sub>		-	8	16		
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C		-	60		
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>		-	-	100	A	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 5 A	-	0.73	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	53	105	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 20 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		65	130	nC	
Reverse Recovery Fall Time	ta			25	-	ns	
Reverse Recovery Rise Time	t <sub>b</sub>			28	-		

#### Notes

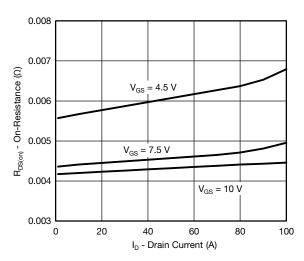
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

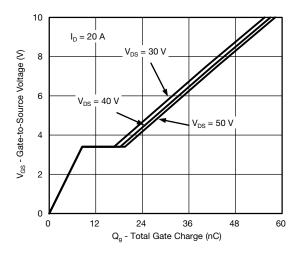




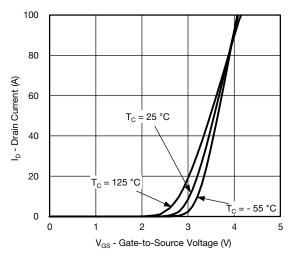
#### **Output Characteristics**



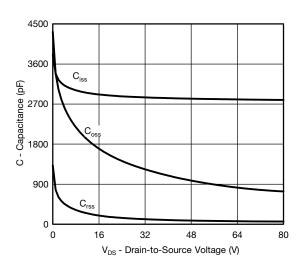
On-Resistance vs. Drain Current



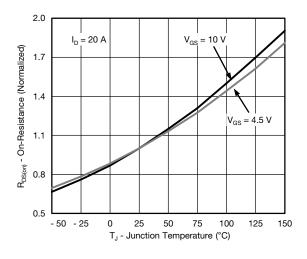
**Gate Charge** 



**Transfer Characteristics** 

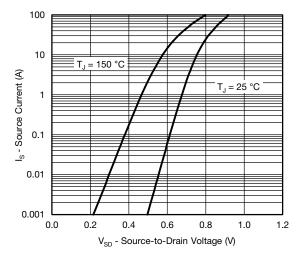


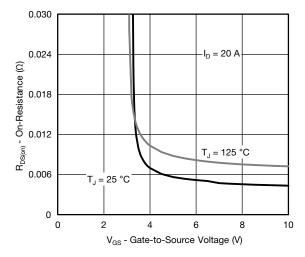
Capacitance



On-Resistance vs. Junction Temperature

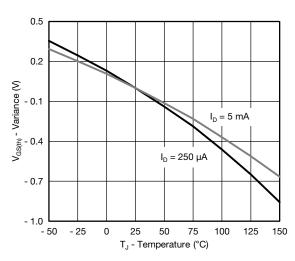


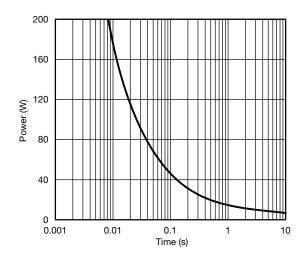




#### Source-Drain Diode Forward Voltage

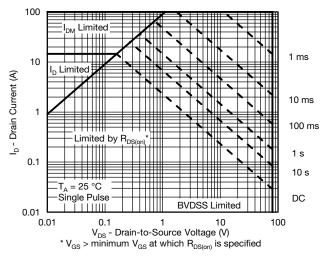






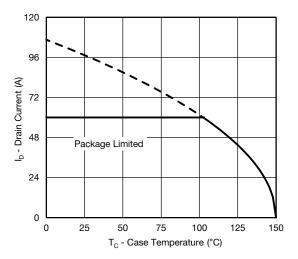
Threshold Voltage

Single Pulse Power, Junction-to-Ambient

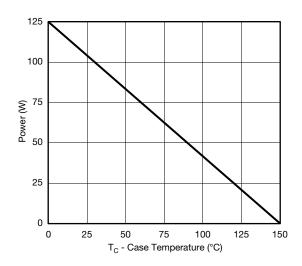


Safe Operating Area, Junction-to-Ambient

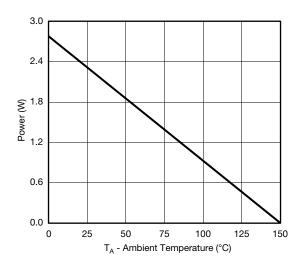




#### **Current Derating\***



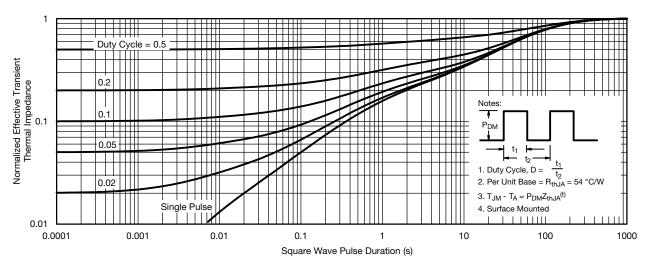




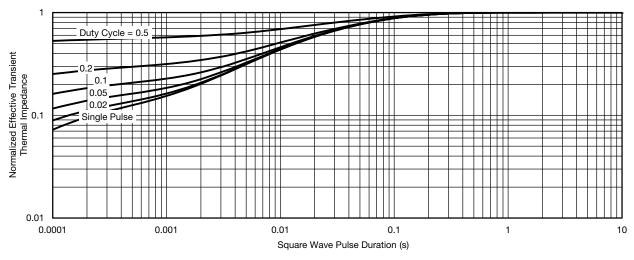
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J \text{ (max.)}} = 150 \,^{\circ}\text{C}$ , using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





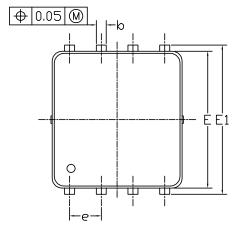
Normalized Thermal Transient Impedance, Junction-to-Ambient

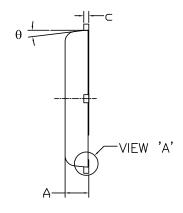


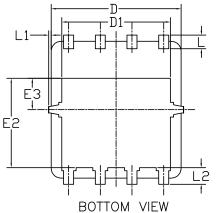
Normalized Thermal Transient Impedance, Junction-to-Case

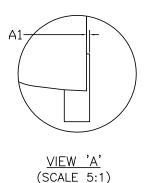


DFN5x6\_8L\_EP1\_P PACKAGE OUTLIN

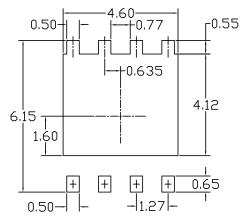








#### RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES			
STWIBULS	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.85	0. 95	1.00	0.033	0.037	0.039	
A1	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
c	0.15	0. 20	0. 25	0.006	0.008	0.010	
D	5. 10	5. 20	5. 30	0. 201	0. 205	0. 209	
D1	4. 25	4. 35	4. 45	0. 167	0. 171	0. 175	
Е	5. 45	5. 55	5. 65	0. 215	0. 219	0. 222	
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242	
E2	3. 525	3. 625	3. 725	0.139	0. 143	0. 147	
E3	1. 175	1. 275	1. 375	0.046	0.050	0.054	
e	1. 27 BSC			0.050 BSC			
L	0.45	0. 55	0.65	0.018	0.022	0.026	
L1	0		0.15	0		0.006	
L2	0.68 REF			0. 027 REF			
θ	0°		10°	0°		10°	

## NOTE

UNIT: mm

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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